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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications,

Details

Product Status	Obsolete
Number of LABs/CLBs	-
Number of Logic Elements/Cells	-
Total RAM Bits	2560
Number of I/O	202
Number of Gates	54000
Voltage - Supply	3V ~ 3.6V, 4.5V ~ 5.5V
Mounting Type	Surface Mount
Operating Temperature	-55°C ~ 125°C (TC)
Package / Case	240-BFQFP
Supplier Device Package	240-PQFP (32x32)
Purchase URL	https://www.e-xfl.com/product-detail/microsemi/a42mx36-1pq240m

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- The Transient Current, page 13 is new (SAR 36930).
- Package names were revised according to standards established in *Package Mechanical Drawings* (SAR 34774)

1.7 Revision 9.0

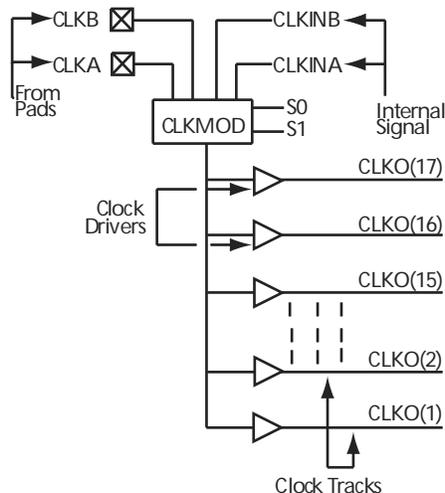
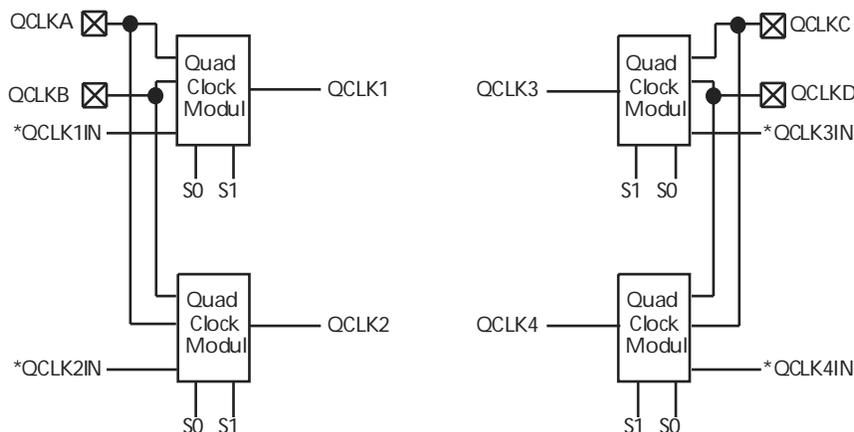
The following is a summary of the changes in revision 9.0 of this document

- In Table 20, page 23, the limits in VI were changed from -0.5 to VCCI + 0.5 to -0.5 to VCCA + 0.5
- In Table 22, page 25, V_{OH} was changed from 3.7 to 2.4 for the min in industrial and military. V_{IH} had V_{CCI} and that was changed to VCCA

1.8 Revision 6.0

The following is a summary of the changes in revision 6.0 of this document.

- The Ease of Integration, page 1 was updated
- The Temperature Grade Offerings, page 5 is new
- The Speed Grade Offerings, page 5 is new
- The General Description, page 6 was updated
- The MultiPlex I/O Modules, page 11 was updated
- The User Security, page 12 was updated
- Table 6, page 13 was updated
- The Power Dissipation, page 14 was updated.
- The Static Power Component, page 14 was updated
- The Equivalent Capacitance, page 15 was updated
- Figure 13, page 17 was updated
- Table 10, page 18 was updated.
- Figure 14, page 18 was updated.
- Table 11, page 19 was updated.

Figure 8 • Clock Networks of 42MX Devices**Figure 9 • Quadrant Clock Network of A42MX36 Devices**

Note: *QCLK1IN, QCLK2IN, QCLK3IN, and QCLK4IN are internally-generated signals.

3.2.5 MultiPlex I/O Modules

42MX devices feature MultiPlex I/Os and support 5.0 V, 3.3 V, and mixed 3.3 V/5.0 V operations.

The MultiPlex I/O modules provide the interface between the device pins and the logic array. Figure 10, page 12 is a block diagram of the 42MX I/O module. A variety of user functions, determined by a library macro selection, can be implemented in the module. (See the *Antifuse Macro Library Guide* for more information.) All 42MX I/O modules contain tristate buffers, with input and output latches that can be configured for input, output, or bidirectional operation.

All 42MX devices contain flexible I/O structures, where each output pin has a dedicated output-enable control (Figure 10, page 12). The I/O module can be used to latch input or output data, or both, providing fast set-up time. In addition, the Designer software tools can build a D-type flip-flop using a C-module combined with an I/O module to register input and output signals. See the *Antifuse Macro Library Guide* for more details.

A42MX24 and A42MX36 devices also offer selectable PCI output drives, enabling 100% compliance with version 2.1 of the PCI specification. For low-power systems, all inputs and outputs are turned off to reduce current consumption to below 500 μ A.

To achieve 5.0 V or 3.3 V PCI-compliant output drives on A42MX24 and A42MX36 devices, a chip-wide PCI fuse is programmed via the Device Selection Wizard in the Designer software (Figure 11, page 12). When the PCI fuse is not programmed, the output drive is standard.

A sample calculation of the absolute maximum power dissipation allowed for a TQ176 package at commercial temperature and still air is given in the following equation

$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{ja} (^\circ\text{C}/\text{W})} = \frac{150^\circ\text{C} - 70^\circ\text{C}}{(28^\circ\text{C})/\text{W}} = 2.86\text{W}$$

EQ 5

The maximum power dissipation for military-grade devices is a function of θ_{jc} . A sample calculation of the absolute maximum power dissipation allowed for CQFP 208-pin package at military temperature and still air is given in the following equation

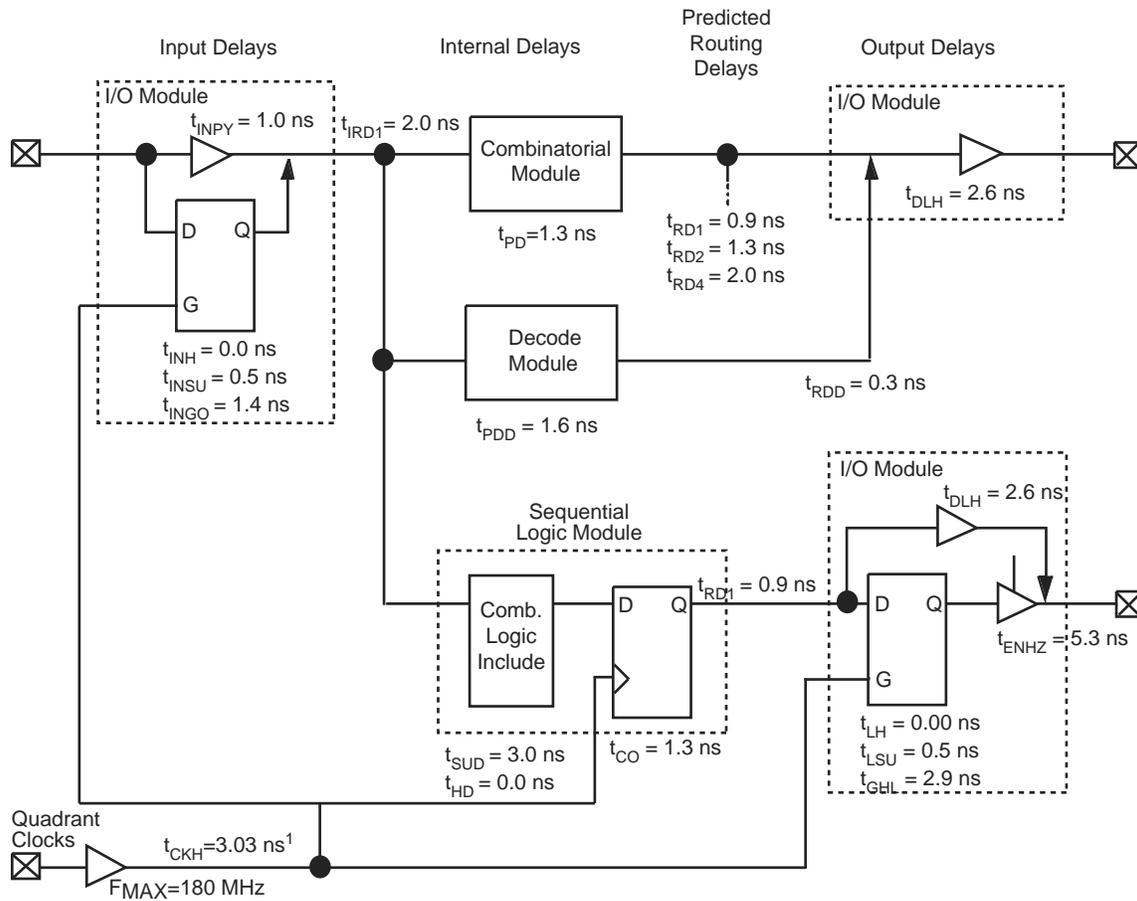
$$\text{MaximumPowerAllowed} = \frac{\text{Max} \cdot \text{junction temp} \cdot (^\circ\text{C}) - \text{Max} \cdot \text{ambient temp} \cdot (^\circ\text{C})}{\theta_{jc} (^\circ\text{C}/\text{W})} = \frac{150^\circ\text{C} - 125^\circ\text{C}}{(6.3^\circ\text{C})/\text{W}} = 3.97\text{W}$$

EQ 6

Table 27 • Package Thermal Characteristics

Plastic Packages	Pin Count	θ_{jc}	θ_{ja}			Units
			Still Air	1.0 m/s 200 ft/min.	2.5 m/s 500 ft/min.	
Plastic Quad Flat Pack	100	12.0	27.8	23.4	21.2	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	144	10.0	26.2	22.8	21.1	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	160	10.0	26.2	22.8	21.1	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	208	8.0	26.1	22.5	20.8	$^\circ\text{C}/\text{W}$
Plastic Quad Flat Pack	240	8.5	25.6	22.3	20.8	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	44	16.0	20.0	24.5	22.0	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	68	13.0	25.0	21.0	19.4	$^\circ\text{C}/\text{W}$
Plastic Leaded Chip Carrier	84	12.0	22.5	18.9	17.6	$^\circ\text{C}/\text{W}$
Thin Plastic Quad Flat Pack	176	11.0	24.7	19.9	18.0	$^\circ\text{C}/\text{W}$
Very Thin Plastic Quad Flat Pack	80	12.0	38.2	31.9	29.4	$^\circ\text{C}/\text{W}$
Very Thin Plastic Quad Flat Pack	100	10.0	35.3	29.4	27.1	$^\circ\text{C}/\text{W}$
Plastic Ball Grid Array	272	3.0	18.3	14.9	13.9	$^\circ\text{C}/\text{W}$
Ceramic Packages						
Ceramic Pin Grid Array	132	4.8	25.0	20.6	18.7	$^\circ\text{C}/\text{W}$
Ceramic Quad Flat Pack	208	2.0	22.0	19.8	18.0	$^\circ\text{C}/\text{W}$
Ceramic Quad Flat Pack	256	2.0	20.0	16.5	15.0	$^\circ\text{C}/\text{W}$

Figure 19 • 42MX Timing Model (Logic Functions Using Quadrant Clocks)



Note: 1. Load-dependent

Note: 2. Values are shown for A42MX36 –3 at 5.0 V worst-case commercial conditions

Figure 22 • AC Test Loads

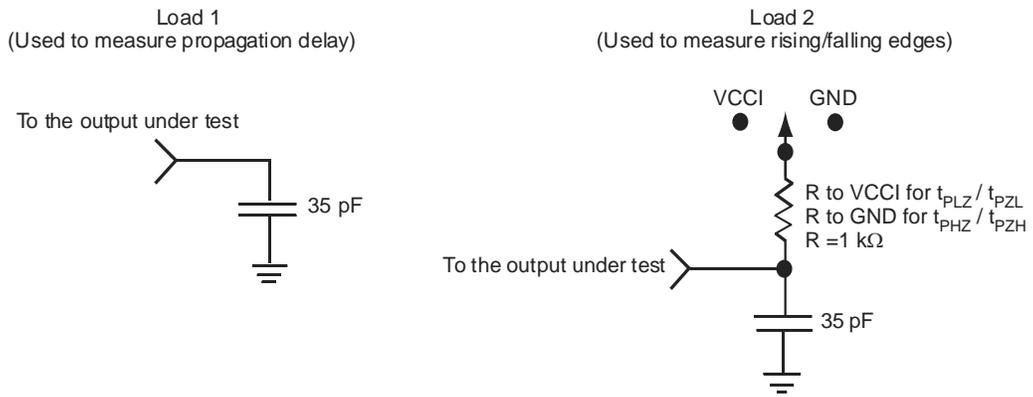


Figure 23 • Input Buffer Delays

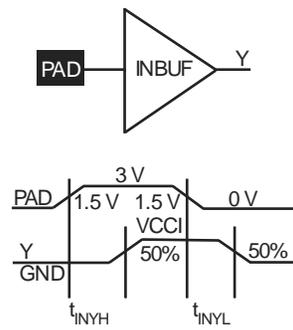


Figure 24 • Module Delays

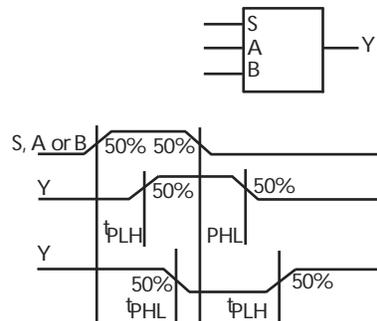
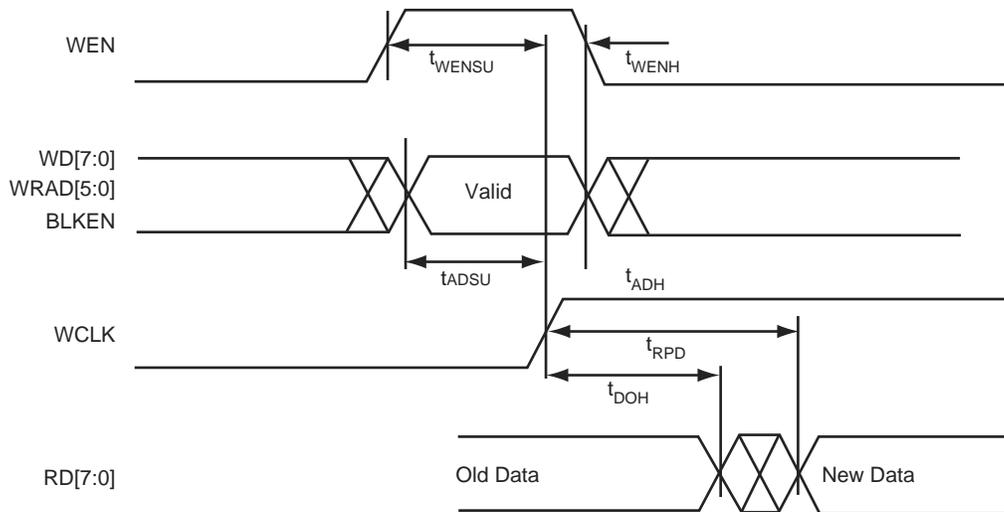


Figure 33 • 42MX SRAM Asynchronous Read Operation—Type 2 (Write Address Controlled)

3.10.7 Predictable Performance: Tight Delay Distributions

Propagation delay between logic modules depends on the resistive and capacitive loading of the routing tracks, the interconnect elements, and the module inputs being driven. Propagation delay increases as the length of routing tracks, the number of interconnect elements, or the number of inputs increases.

From a design perspective, the propagation delay can be statistically correlated or modeled by the fanout (number of loads) driven by a module. Higher fanout usually requires some paths to have longer routing tracks.

The MX FPGAs deliver a tight fanout delay distribution, which is achieved in two ways: by decreasing the delay of the interconnect elements and by decreasing the number of interconnect elements per path.

Microsemi's patented antifuse offers a very low resistive/capacitive interconnect. The antifuses, fabricated in 0.45 μm lithography, offer nominal levels of 100 Ω resistance and 7.0 fF capacitance per antifuse.

MX fanout distribution is also tight due to the low number of antifuses required for each interconnect path. The proprietary architecture limits the number of antifuses per path to a maximum of four, with 90 percent of interconnects using only two antifuses.

3.11 Timing Characteristics

Device timing characteristics fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all MX devices. Internal routing delays are device-dependent; actual delays are not determined until after place-and-route of the user's design is complete. Delay values may then be determined by using the Designer software utility or by performing simulation with post-layout delays.

3.11.1 Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most timing critical paths. Critical nets are determined by net property assignment in Microsemi's Designer software prior to placement and routing. Up to 6% of the nets in a design may be designated as critical.

3.11.2 Long Tracks

Some nets in the design use long tracks, which are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes four antifuse connections, which increase capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically, up to 6 percent of nets in a fully utilized device require long tracks. Long tracks add

Table 36 • A40MX04 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCC = 4.75 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{ENLZ} Enable Pad LOW to Z		5.9		6.8		7.7		9.0		12.6	ns
d _{TLH} Delta LOW to HIGH		0.02		0.02		0.03		0.03		0.04	ns/pF
d _{THL} Delta HIGH to LOW		0.03		0.03		0.03		0.04		0.06	ns/pF

Table 38 • A42MX09 Timing Characteristics (Nominal 5.0 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 4.75 V, T_J = 70°C)

Parameter / Description	-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
t _{WASYN} Flip-Flop (Latch) Asynchronous Pulse Width	4.5		4.9		5.6		6.6		9.2		ns
t _A Flip-Flop Clock Input Period	3.5		3.8		4.3		5.1		7.1		ns
t _{INH} Input Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{INSU} Input Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
t _{OUTH} Output Buffer Latch Hold	0.0		0.0		0.0		0.0		0.0		ns
t _{OUTSU} Output Buffer Latch Set-Up	0.3		0.3		0.4		0.4		0.6		ns
f _{MAX} Flip-Flop (Latch) Clock Frequency		268		244		224		195		117	MHz

Table 45 • A42MX36 Timing Characteristics (Nominal 3.3 V Operation) (continued)(Worst-Case Commercial Conditions, VCCA = 3.0 V, T_J = 70°C)

Parameter / Description		-3 Speed		-2 Speed		-1 Speed		Std Speed		-F Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Input Module Predicted Routing Delays²												
t _{IRD1}	FO = 1 Routing Delay		2.8	3.1	3.5	4.1	5.7	ns				
t _{IRD2}	FO = 2 Routing Delay		3.2	3.5	4.1	4.8	6.7	ns				
t _{IRD3}	FO = 3 Routing Delay		3.7	4.1	4.7	5.5	7.7	ns				
t _{IRD4}	FO = 4 Routing Delay		4.2	4.6	5.3	6.2	8.7	ns				
t _{IRD8}	FO = 8 Routing Delay		6.1	6.8	7.7	9.0	12.6	ns				
Global Clock Network												
t _{CKH}	Input LOW to HIGH	FO = 32	4.6	5.1	5.7	6.7	9.3	ns				
		FO = 635	5.0	5.6	6.3	7.4	10.3	ns				
t _{CKL}	Input HIGH to LOW	FO = 32	5.3	5.9	6.7	7.8	11.0	ns				
		FO = 635	6.8	7.6	8.6	10.1	14.1	ns				
t _{PWH}	Minimum Pulse Width HIGH	FO = 32	2.5	2.7	3.1	3.6	5.1	ns				
		FO = 635	2.8	3.1	3.5	4.1	5.7	ns				
t _{PWL}	Minimum Pulse Width LOW	FO = 32	2.5	2.7	3.1	3.6	5.1	ns				
		FO = 635	2.8	3.1	3.5	4.1	5.7	ns				
t _{CKSW}	Maximum Skew	FO = 32	1.0	1.2	1.3	1.5	2.2	ns				
		FO = 635	1.0	1.2	1.3	1.5	2.2	ns				
t _{SUEXT}	Input Latch External Set-Up	FO = 32	0.0	0.0	0.0	0.0	0.0	ns				
		FO = 635	0.0	0.0	0.0	0.0	0.0	ns				
t _{HEXT}	Input Latch External Hold	FO = 32	4.0	4.4	5.0	5.9	8.2	ns				
		FO = 635	4.6	5.2	5.9	6.9	9.6	ns				
t _P	Minimum Period (1/f _{MAX})	FO = 32	9.2	10.2	11.1	12.7	21.2	ns				
		FO = 635	9.9	11.0	12.0	13.8	23.0	ns				
f _{MAX}	Maximum Datapath Frequency	FO = 32	108	98	90	79	47	MHz				
		FO = 635	100	91	83	73	44	MHz				
TTL Output Module Timing⁵												
t _{DLH}	Data-to-Pad HIGH		3.6	4.0	4.5	5.3	7.4	ns				
t _{DHL}	Data-to-Pad LOW		4.2	4.6	5.2	6.2	8.6	ns				
t _{ENZH}	Enable Pad Z to HIGH		3.7	4.2	4.7	5.5	7.7	ns				
t _{ENZL}	Enable Pad Z to LOW		4.1	4.6	5.2	6.1	8.5	ns				
t _{ENHZ}	Enable Pad HIGH to Z		7.34	8.2	9.3	10.9	15.3	ns				
TTL Output Module Timing⁵												
t _{ENLZ}	Enable Pad LOW to Z		6.9	7.6	8.7	10.2	14.3	ns				
t _{GLH}	G-to-Pad HIGH		4.9	5.5	6.2	7.3	10.2	ns				
t _{GHL}	G-to-Pad LOW		4.9	5.5	6.2	7.3	10.2	ns				
t _{LSU}	I/O Latch Output Set-Up		0.7	0.7	0.8	1.0	1.4	ns				
t _{LH}	I/O Latch Output Hold		0.0	0.0	0.0	0.0	0.0	ns				
t _{LCO}	I/O Latch Clock-to-Out (Pad-to-Pad) 32 I/O		7.9	8.8	10.0	11.8	16.5	ns				

Clock signal to shift the Boundary Scan Test (BST) data into the device. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDI, I/O Test Data In

Serial data input for BST instructions and data. Data is shifted in on the rising edge of TCK. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TDO, I/O Test Data Out

Serial data output for BST instructions and test data. This pin functions as an I/O when "Reserve JTAG" is not checked in the Designer Software. BST pins are only available in A42MX24 and A42MX36 devices.

TMS, I/O Test Mode Select

The TMS pin controls the use of the IEEE 1149.1 Boundary Scan pins (TCK, TDI, TDO). In flexible mode when the TMS pin is set LOW, the TCK, TDI and TDO pins are boundary scan pins. Once the boundary scan pins are in test mode, they will remain in that mode until the internal boundary scan state machine reaches the "logic reset" state. At this point, the boundary scan pins will be released and will function as regular I/O pins. The "logic reset" state is reached 5 TCK cycles after the TMS pin is set HIGH. In dedicated test mode, TMS functions as specified in the IEEE 1149.1 specifications. IEEE JTAG specification recommends a 10k Ω pull-up resistor on the pin. BST pins are only available in A42MX24 and A42MX36 devices.

VCC, Supply Voltage

Input supply voltage for 40MX devices

VCCA, Supply Voltage

Supply voltage for array in 42MX devices

VCCI, Supply Voltage

Supply voltage for I/Os in 42MX devices

WD, I/O Wide Decode Output

When a wide decode module is used in a 42MX device this pin can be used as a dedicated output from the wide decode module. This direct connection eliminates additional interconnect delays associated with regular logic modules. To implement the direct I/O connection, connect an output buffer of any type to the output of the wide decode macro and place this output on one of the reserved WD pins.

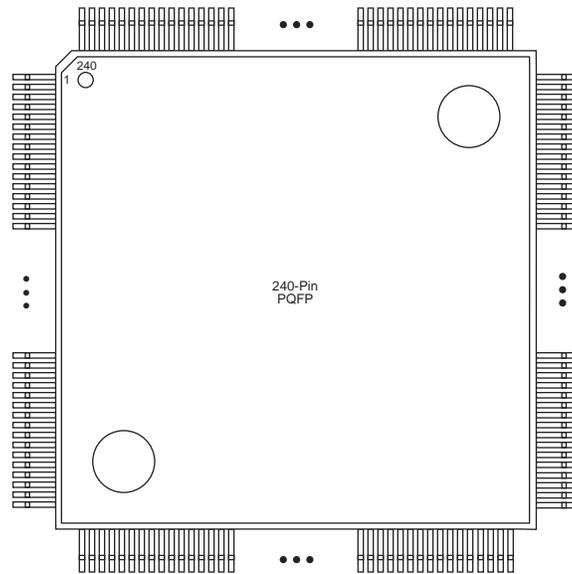
Table 50 • PQ 100

PQ100				
Pin Number	A40MX02 Function	A40MX04 Function	A42MX09 Function	A42MX16 Function
93	VCC	VCC	I/O	I/O
94	VCC	VCC	PRB, I/O	PRB, I/O
95	NC	I/O	I/O	I/O
96	NC	I/O	GND	GND
97	NC	I/O	I/O	I/O
98	SDI, I/O	SDI, I/O	I/O	I/O
99	DCLK, I/O	DCLK, I/O	I/O	I/O
100	PRA, I/O	PRA, I/O	I/O	I/O

Table 53 • PQ208

PQ208			
Pin Number	A42MX16 Function	A42MX24 Function	A42MX36 Function
206	I/O	I/O	I/O
207	DCLK, I/O	DCLK, I/O	DCLK, I/O
208	I/O	I/O	I/O

Figure 45 • PQ240



Note: This figure shows the 240-Pin PQFP Package top view.

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
1	I/O
2	DCLK, I/O
3	I/O
4	I/O
5	I/O
6	WD, I/O
7	WD, I/O
8	VCCI
9	I/O
10	I/O
11	I/O
12	I/O
13	I/O
14	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
15	QCLKC, I/O
16	I/O
17	WD, I/O
18	WD, I/O
19	I/O
20	I/O
21	WD, I/O
22	WD, I/O
23	I/O
24	PRB, I/O
25	I/O
26	CLKB, I/O
27	I/O
28	GND
29	VCCA
30	VCCI
31	I/O
32	CLKA, I/O
33	I/O
34	PRA, I/O
35	I/O
36	I/O
37	WD, I/O
38	WD, I/O
39	I/O
40	I/O
41	I/O
42	I/O
43	I/O
44	I/O
45	QCLKD, I/O
46	I/O
47	WD, I/O
48	WD, I/O
49	I/O
50	I/O
51	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
126	WD, I/O
127	I/O
128	VCCI
129	I/O
130	I/O
131	I/O
132	WD, I/O
133	WD, I/O
134	I/O
135	QCLKB, I/O
136	I/O
137	I/O
138	I/O
139	I/O
140	I/O
141	I/O
142	WD, I/O
143	WD, I/O
144	I/O
145	I/O
146	I/O
147	I/O
148	I/O
149	I/O
150	VCCI
151	VCCA
152	GND
153	I/O
154	I/O
155	I/O
156	I/O
157	I/O
158	I/O
159	WD, I/O
160	WD, I/O
161	I/O
162	I/O

Table 54 • PQ240

PQ240	
Pin Number	A42MX36 Function
200	I/O
201	I/O
202	I/O
203	I/O
204	I/O
205	I/O
206	VCCA
207	I/O
208	I/O
209	VCCA
210	VCCI
211	I/O
212	I/O
213	I/O
214	I/O
215	I/O
216	I/O
217	I/O
218	I/O
219	VCCA
220	I/O
221	I/O
222	I/O
223	I/O
224	I/O
225	I/O
226	I/O
227	VCCI
228	I/O
229	I/O
230	I/O
231	I/O
232	I/O
233	I/O
234	I/O
235	I/O
236	I/O

Table 57 • TQ176

TQ176			
Pin Number	A42MX09 Function	A42MX16 Function	A42MX24 Function
84	I/O	I/O	WD, I/O
85	I/O	I/O	WD, I/O
86	NC	I/O	I/O
87	SDO, I/O	SDO, I/O	SDO, TDO, I/O
88	I/O	I/O	I/O
89	GND	GND	GND
90	I/O	I/O	I/O
91	I/O	I/O	I/O
92	I/O	I/O	I/O
93	I/O	I/O	I/O
94	I/O	I/O	I/O
95	I/O	I/O	I/O
96	NC	I/O	I/O
97	NC	I/O	I/O
98	I/O	I/O	I/O
99	I/O	I/O	I/O
100	I/O	I/O	I/O
101	NC	NC	I/O
102	I/O	I/O	I/O
103	NC	I/O	I/O
104	I/O	I/O	I/O
105	I/O	I/O	I/O
106	GND	GND	GND
107	NC	I/O	I/O
108	NC	I/O	TCK, I/O
109	LP	LP	LP
110	VCCA	VCCA	VCCA
111	GND	GND	GND
112	VCCI	VCCI	VCCI
113	VCCA	VCCA	VCCA
114	NC	I/O	I/O
115	NC	I/O	I/O
116	NC	VCCA	VCCA
117	I/O	I/O	I/O
118	I/O	I/O	I/O
119	I/O	I/O	I/O
120	I/O	I/O	I/O

Table 59 • CQ256

CQ256	
Pin Number	A42MX36 Function
59	I/O
60	VCCA
61	GND
62	GND
63	NC
64	NC
65	NC
66	I/O
67	SDO, TDO, I/O
68	I/O
69	WD, I/O
70	WD, I/O
71	I/O
72	VCCI
73	I/O
74	I/O
75	I/O
76	WD, I/O
77	GND
78	WD, I/O
79	I/O
80	QCLKB, I/O
81	I/O
82	I/O
83	I/O
84	I/O
85	I/O
86	I/O
87	WD, I/O
88	WD, I/O
89	I/O
90	I/O
91	I/O
92	I/O
93	I/O
94	I/O
95	VCCI

Table 61 • PG132

PG132	
Pin Number	A42MX09 Function
B3	I/O
A2	I/O
C3	DCLK
B5	GND A
E12	GND A
J2	GND A
M9	GND A
B9	GND I
C5	GND I
E11	GND I
F4	GND I
J3	GND I
J11	GND I
L5	GND I
L9	GND I
C9	GND Q
E3	GND Q
K12	GND Q
D7	VCCA
G3	VCCA
G10	VCCA
L7	VCCA
C7	VCCI
G2	VCCI
G11	VCCI
K7	VCCI